

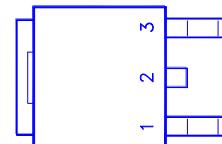
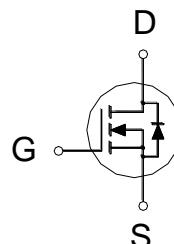
NIKO-SEM**N-Channel Enhancement Mode
Field Effect Transistor****P5015CD**

TO-252

Halogen-Free & Lead-Free

**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
150V	50mΩ	23A



1. GATE
2. DRAIN
3. SOURCE

ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS		UNITS
Drain-Source Voltage		V_{DS}	150		V
Gate-Source Voltage		V_{GS}	± 12		V
Continuous Drain Current	$T_C = 25^\circ\text{C}$	I_D	23		A
	$T_C = 100^\circ\text{C}$		14		
Pulsed Drain Current ¹		I_{DM}	80		
Avalanche Current		I_{AS}	9.6		
Avalanche Energy	$L = 1\text{mH}$	E_{AS}	46		mJ
Power Dissipation	$T_C = 25^\circ\text{C}$	P_D	71		W
	$T_C = 100^\circ\text{C}$		28		
Junction & Storage Temperature Range		T_J, T_{stg}	-55 to 150		°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		1.75	
Junction-to-Ambient	$R_{\theta JA}$		62.5	°C / W

¹Pulse width limited by maximum junction temperature.

ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$	150			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	0.65	0.95	1.3	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0\text{V}, V_{GS} = \pm 12\text{V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 150\text{V}, V_{GS} = 0\text{V}$			1	
		$V_{DS} = 100\text{V}, V_{GS} = 0\text{V}, T_J = 125^\circ\text{C}$			10	μA

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Drain-Source On-State Resistance ¹	$R_{DS(ON)}$	$V_{GS} = 10V, I_D = 10A$	33	50	$m\Omega$
		$V_{GS} = 4.5V, I_D = 10A$	33.2	55	
		$V_{GS} = 3V, I_D = 10A$	33.5	60	
		$V_{GS} = 2.5V, I_D = 10A$	34	80	
Forward Transconductance ¹	g_{fs}	$V_{DS} = 5V, I_D = 10A$		103	S
DYNAMIC					
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 75V, f = 1MHz$	3910		pF
Output Capacitance	C_{oss}		100		
Reverse Transfer Capacitance	C_{rss}		66		
Gate Resistance	R_g	$V_{GS} = 0V, V_{DS} = 0V, f = 1MHz$	0.8		Ω
Total Gate Charge ²	Q_g	$V_{GS} = 10V, V_{DS} = 75V, I_D = 10A$	105		nC
Gate-Source Charge ²	Q_{gs}		8.4		
Gate-Drain Charge ²	Q_{gd}		17		
Turn-On Delay Time ²	$t_{d(on)}$	$V_{DS} = 75V$ $I_D \geq 10A, V_{GS} = 10V, R_{GEN} = 6\Omega$	14		nS
Rise Time ²	t_r		33		
Turn-Off Delay Time ²	$t_{d(off)}$		166		
Fall Time ²	t_f		103		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ C$)					
Continuous Current	I_S			23	A
Forward Voltage ¹	V_{SD}	$I_F = 10A, V_{GS} = 0V$		1	V
Reverse Recovery Time	t_{rr}	$I_F = 10A, dI_F/dt = 100A/\mu S$	36		nS
Reverse Recovery Charge	Q_{rr}		39		

¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.

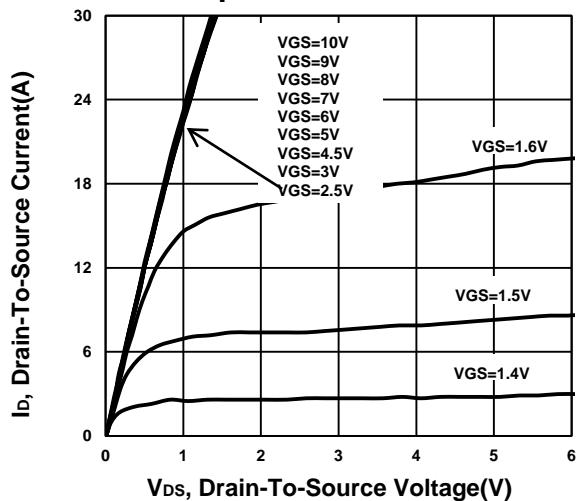
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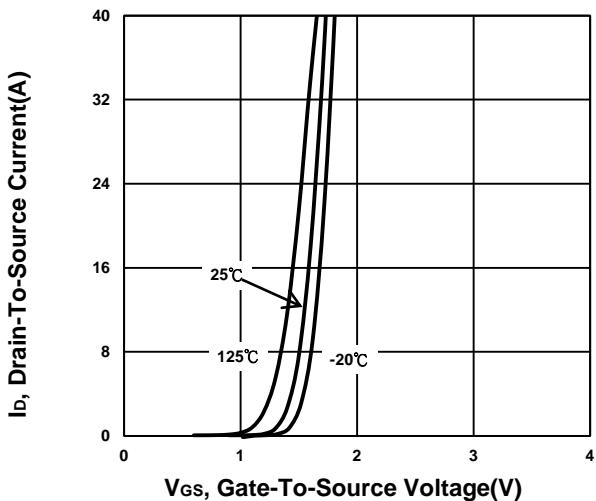
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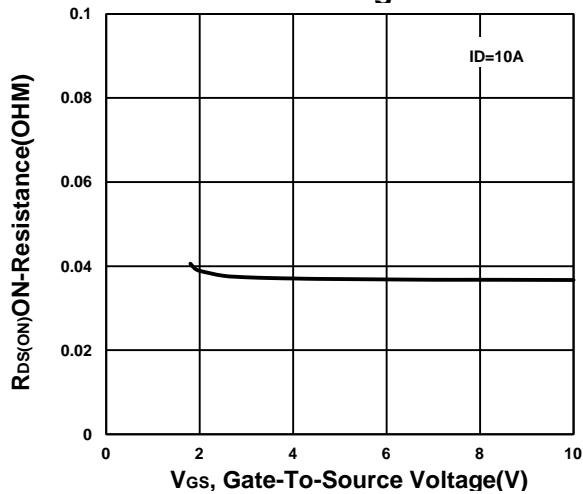
Output Characteristics



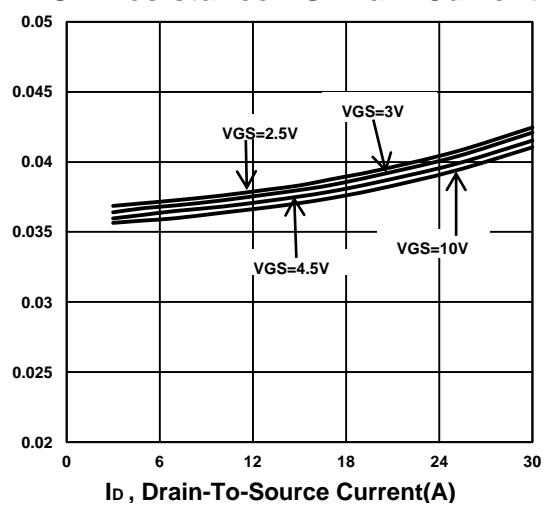
Transfer Characteristics



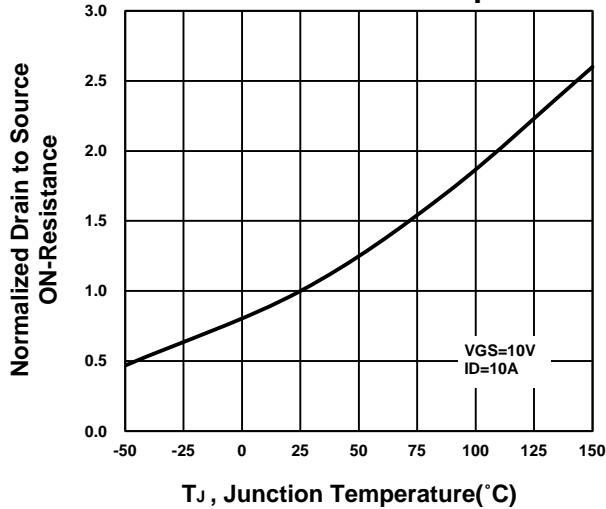
On-Resistance VS Gate-to-Source Voltage



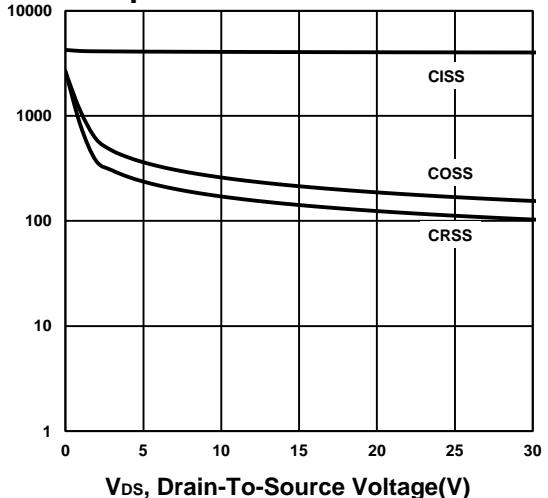
On-Resistance VS Drain Current



On-Resistance VS Temperature



Capacitance Characteristic



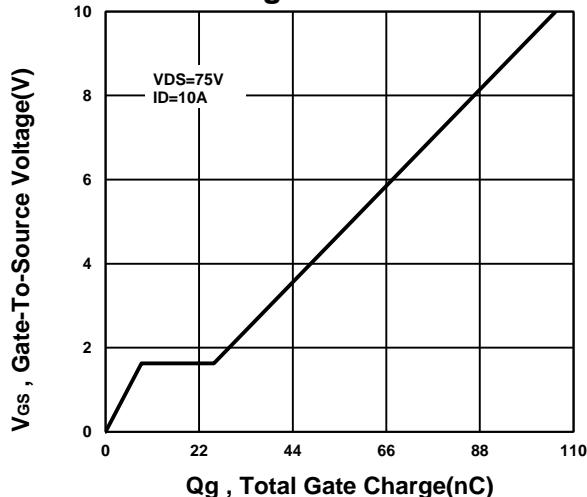
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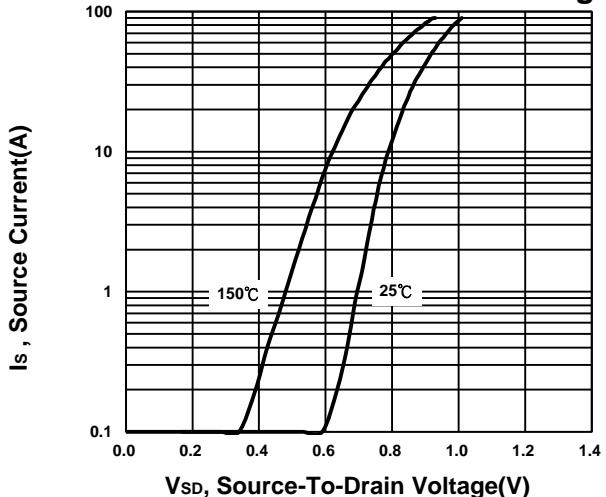
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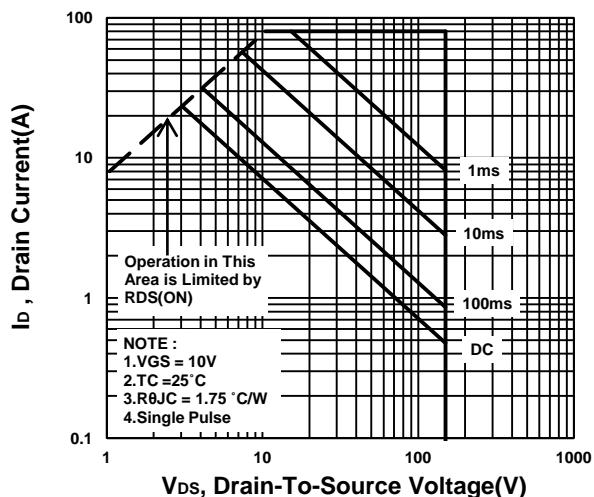
Gate charge Characteristics



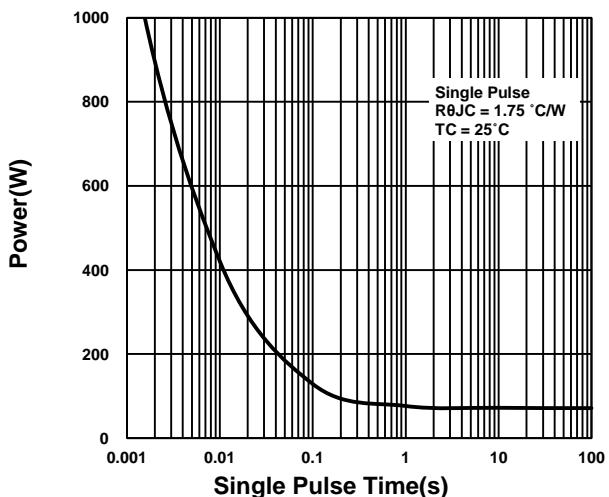
Source-Drain Diode Forward Voltage



Safe Operating Area



Single Pulse Maximum Power Dissipation



Transient Thermal Response Curve

